

Efficient Self-Learning Techniques for SAT-Based Test Generation

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Outline

- Introduction
- SAT-Based Directed Test Generation
 - Test Generation using Model Checking
 - Test Generation using SAT-Based BMC
- Our Self-Learning Techniques
 - Motivation and Overview
 - Learning Oriented Partitioning Heuristics
 - Self-Learning Based Test Generation
- Experiments
- Conclusions

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Functional Validation of SoC Designs



Simulation-based Validation



Why Directed Test Generation

Activate desired behavior with efficient tests



Need for automated generation of directed tests

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Automated Directed Test Generation



Directed test generation based on the automation of model checking techniques.

Test Generation using Model Checking

Example: Generate a directed test to stall a decode unit (ID)



Problem: Test generation is very costly or not possible in many scenarios in the presence of complex SoCs and/or complex properties.

Approach: Exploit some learning to reduce complexity

- Reduce TG time & memory requirements
- Enable test generation in complex scenarios

SAT-based Bounded Model Checking

- Test generation needs to consider safety properties
- The safety property *P* is valid up to cycle *k* iff Ω(*k*) is not satisfiable.

$$\Omega(k) = I(S_0) \wedge \bigwedge_{i=0}^{k-1} R(S_i, S_{i+1}) \wedge \bigvee_{i=0}^{k} \neg P(s_i)$$

$$\stackrel{p}{\bullet} \xrightarrow{p} \underbrace{p}_{s_1} \xrightarrow{p} \underbrace{p}_{s_2} \underbrace{\dots}_{s_{k-1}} \xrightarrow{p} \underbrace{p}_{s_k}$$

If Ω(k) is satisfiable, then we can get an assignment which can be translated to a test.

DPLL Search Procedure



SAT search time can be improved if we can reduce: - the number of bad decisions at early stage, and - the number of long distance backtracks.

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Property Learning Techniques



M. Chen and P. Mishra. Functional Test Generation using Efficient Property Clustering and Learning Techniques. *TCAD 2010*.
M. Chen and P. Mishra. Efficient Decision Ordering Techniques for SAT-based Test Generation. *DATE 2010*.

Property Decomposition Techniques



Koo et al. Functional Test Generation using Property Decomposition Techniques. ACM *TECS*, 2009M. Chen and P. Mishra. Decision ordering based property decomposition for functional test generation. *DATE*, 2011





Problems: How to achieve the beneficial learning efficiently? - Which kind of learning can be forwarded?

- How can we achieve and utilize such kinds of learnings?

Conflict Clause Based Learning



 Conflict clause can be treated as the knowledge learned during the SAT solving. It is a restriction of the variable assignment.

Decision Ordering Based Learning



Ordering: a, a', b, b', c, c'

Ordering: a, a', b, b', c, c'

Without Learning, 7 conflicts in SAT2.

Decision Ordering Based Learning



Ordering: a, a', b, b', c, c'

Ordering: b', b, c', c, a, a'

With bit value+ variable order learning, 1 conflict in SAT2.

Learn from the Structure of BMC Formulas





Learn from the Structure of BMC Formulas



a) A deduction for a transition variable

Reasons for long-distance backtracks:

The constraint imposed by the transition part T is weak.
A bad decision is made too early but detected too late.

By our observation, conflict clause and decision ordering are two promising self-learning candidates to address the above two problems.

Learning from Segmental Partitioning



Learning from Incremental Partitioning



Learn from the Structure of CNF clauses

- For a set of small CNF clauses, the impact of a variable decision can be propagate instantly. Only a few decision levels are involved in the searching (avoid long-distance backtracking).
- We take clause size into account to derive high-quality conflict clauses.
 - A set of small CNF clauses has a high chance to derive small-size conflict clauses.
 - Smaller conflict clauses can prune more search space.

Learning from Clause Size Aware Partitioning



Test Generation using Self-Learning Techniques



Self-Learning Based Test Generation

Input: i) Formal model *D* and property *P* with the bound *Bound_P* ii) Partitioning type *type* and the number of patitions *n* Output: A test *t_P* to satisfy the property *P*

- 1. Initialize IBucket[1..n] and vStat[1..sz][];
- 2. CNF=BMC(D, P, Boundp);
- **3.** $\{p_1, p_2, ..., p_n\} = Partition(CNF, type, n);$
- 4. for i is from 1 to n do
 - (Assigni, confi) = SAT(pi, IBucket[1..i-1], vStat);
 - ② IBucket[i] = confi;
 - 3 for j is from 1 to sz do
 - **a) if** (assigni[j]==0) vStat[j][2]++;
 - **b) else if** (assigni[j]==1) vStat[j][1]++;
- **5**. (tp,) = SAT(CNF, IBucket[1..n], vStat);
- 6. Return tp.

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Experiments

- The experiments were conducted on a Linux PC with a 3.3GHz CPU and 4G RAM.
- We modified the SAT solvers MiniSAT2.2 and zChaff to incorporate our paritioning and self-learning techniques.
- In our experiments, all the SAT instances are divided into 4 partitions by default. For conflict clauses based self-learning, we only forward the conflict clauses whose size is smaller than 9.

Case Study 1: DLX+OSES

 The benchmark is a set of SAT instances derived from a MIPS processor (DLX), and an online stock exchance system (OSES). All the SAT instances are generated using the tool NuSMV.

SAT	MiniSAT[15]	Segmental Partitioning ([15]/[16])			Incremental Partitioning ([15]/[16])			C. S. A. Partitioning (15]/[16])	Max
Instance	/zChaff[16]	cls	var	cls+var	cls	var	cls+var	cls	var	cls+var	Speedup
DLX-1	1.9/104.5	3.6/72.8	4.3/22.2	3.3 /23.0	4.6/133.4	4.9/28.6	3.7/24.6	3.5/23.1	4.3/6.7	3.4/ 6.2	0.6/16.9
DLX-2	1.5/58.0	3.5/58.5	3.3/20.8	3.1 /19.0	4.3/90.0	4.5/19.1	3.8/13.9	3.8/35.3	4.1/9.5	3.2/ 5.7	0.5/10.2
DLX-3	0.8/32.4	1.7/26.3	2.1/12.7	1.6 /15.2	2.1/189.2	2.0/8.7	2.0/11.8	1.9/16.9	2.1/5.0	1.8/3.2	0.5/10.1
DLX-4	0.2/2.1	0.5/2.4	0.6/0.8	0.5/0.5	0.7/1.5	0.6/0.7	0.5 /0.6	0.5/1.4	0.5/0.8	0.5/0.7	0.4/4.2
DLX-5	0.6/7.9	1.3/6.1	1.3/4.2	1.3/3.8	1.4/9.6	1.5/4.9	1.2/2.8	1.1/6.6	1.3/2.9	1.0/2.7	0.6/2.9
DLX-6	1.1/101.3	2.6/105.0	3.0/35.5	2.7/31.0	3.2/106.1	2.8/27.2	2.9/25.6	2.6/71.7	2.6/3.7	2.3/2.9	0.5/34.9
OSES-1	0.6/5.5	0.3 /0.6	0.4/18.5	0.4/4.2	0.3/6.3	0.4/1.7	0.3/0.8	0.4/1.0	0.4/0.5	0.4/0.7	2.0/11.0
OSES-2	0.6/209.3	0.5/80.2	2.1/200.1	0.9/290.6	2.2/131.1	1.6/177.6	1.1/249.0	1.1/246.6	2.3/73.1	1.0/24.8	1.2/8.4
OSES-3	4.7/121.7	1.7/89.8	9.5/181.5	1.0/238.9	0.9 /89.5	2.0/140.8	9.2/269.5	1.9/74.5	1.3/6.7	5.4/35.3	5.2/18.2
OSES-4	0.9/28.8	3.5/47.3	7.9/91.4	4.0/99.6	4.0/39.0	3.4/45.2	1.0 /8.7	5.1/36.4	18.6/ 0.8	5.0/0.9	0.9/32.0
OSES-5	0.1/21.8	0.2 /20.2	0.3/8.8	0.3/5.2	0.6/12.0	0.3/3.5	0.4/2.7	0.4/21.1	0.3/0.6	0.3/0.7	0.5/36.3
OSES-6	0.9/53.8	0.3 /74.4	0.4/76.5	0.4/67.4	0.7/122.8	0.5/15.2	0.7/78.8	1.2/136.4	1.4/ 1.7	1.5/2.3	3.0/31.6

• Since the test generation time using MiniSAT without any leanring is small, the extra self-learning does not show significant improvement.

Case Study 1: DLX+OSES



Indications: Test generation complexity is significantly reduced in zChaff.

- Reduction of long-distance backtracking
- Reduction of bad decisions

Case Study 2: PIPE Processor Design

The benchmark is a set of SAT instances from 10 buggy variants of 12-pipelined processors named PIPE-SAT-1.1.

SAT	MiniSAT[15]	Segmental Partitioning ([15]/[16])			Incremental Partitioning ([15]/[16])			C. S. A. Partitioning ([15]/[16])			Max
Instance	/zChaff[16]	cls	var	cls+var	cls	var	cls+var	cls	var	cls+var	Speedup
PIPE1	12/854	28/488	234/761	190/572	8/507	1/242	1/924	26/844	2/7	2/8	12.0/122.0
PIPE2	1/1090	1/2085	1/421	1/1	11/943	1 /174	1/217	1/1124	1 /11	1 /11	1.0/1090.0
PIPE3	15/524	8/879	169/1185	144/1495	8/692	1/521	1/142	16/707	4/276	4/276	15.0/3.7
PIPE4	6/670	36/77	1055/162	1/12	5/311	NA/4	118/4	18/684	2/237	2/236	6.0/167.5
PIPE5	5/395	2/1345	3/2544	2/2613	9/90	2/595	10/1240	16/401	2/55	4/55	2.5/7.2
PIPE6	1/1	1/98	4/106	11/55	1/2	2/122	4/142	1/1	1/1	1/1	1.0/1.0
PIPE7	13/1117	284/505	322/2069	112/1184	450/681	6/1188	4 /162	13/1059	4/38	4/39	3.3/29.4
PIPE8	2/73	6/1	44/69	91/61	7/110	NA/75	NA/76	9/73	6/30	11/30	0.3/73
PIPE9	30/3897	32/2522	2/404	2/395	43/421	3/1295	1/964	6/3874	1/1022	1/1020	30.0/9.9
PIPE10	174/907	112/647	672/973	4/497	111/446	2/139	2/118	17/661	4/148	4/147	87.0/7.7

 Table 2: Test Generation Results for PIPE Processors

 Both the modified zChaff and MiniSAT shows that our self-learnings can achieve significant improvement.

Case Study 3: UNSAT PIPE_000

• We also conducted the experiment on a set of bigger variants of the pipe_ooo benchmarks named PIPE-OOO-UNSAT-1.1.

SAT	MiniSAT[15]	Segmental Partitioning ([15]/[16])			Incremental Partitioning ([15]/[16])			C. S. A. Partitioning ([15]/[16])			Max
Instance	/zChaff[16]	cls	var	cls+var	cls	var	cls+var	cls	var	cls+var	Speedup
pipe2-000	0.3/0.06	0.1/0.05	0.04 /0.08	0.05/0.09	0.1/0.06	0.1/0.10	0.1/0.10	0.3/0.08	0.1/0.19	0.1/0.13	7.5/1.2
pipe3-000	10.7/0.8	12.5/0.9	6.7/0.9	5.9/1.1	11.6/1.1	12.5/1.0	8.0/0.9	8.4/ 0.8	0.8 /1.5	1.2/1.1	13.4/1.0
pipe4-000	94/6	142/4	118/3	111/4	114/3	77/4	197/4	50/6	13/5	10/5	9.4/2.0
pipe5-000	280/18	356/15	64/15	47 /14	498/14	NA/12	1065/11	476/13	51/18	62/21	6.0/1.6
pipe6-000	731/69	NA/65	NA/64	NA/61	279/67	NA/50	NA/48	645/66	74/78	70 /70	10.4/1.4
pipe7-000	1016/266	702 /278	NA/285	NA/294	NA/303	NA/199	NA/208	NA/285	NA/304	NA/295	1.4/1.3
pipe8-000	NA/1107	NA/1330	NA/1083	NA/1104	NA/1387	NA/772	NA/684	NA/1326	NA/1354	NA/1334	1.4/1.6
pipe9-000	NA/1697	NA/1716	NA/1565	NA/1656	NA/1688	NA/940	NA/989	NA/1497	NA/2005	NA/1913	NA/1.8

Table 3: SAT Solving Results for UNSAT Instances of PIPE Processors

 Interestingly, our approach can also benifit the UNSAT instance checking. We can find that zChaff outperforms MiniSAT in this benchmark, and our self-learning techniques can achieve an up to 13.4 times improvement using MiniSAT and 2 times improvement using zChaff.

Evaluation of the number of partitions



Indications:

-For zChaff, the methods using 4 partitions show a better performance for these three benchmarks.

- For MiniSAT, the approaches using 2 partitions or 4 partitions are good enough for test generation.

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Conclusions

- Functional validation is a major bottleneck
 - SAT-based approaches are promising for automated test generation.
- Proposed efficient self-learning techniques for automated generation of directed tests
 - Investigated two kinds of learning objects.
 - Developed three learning-oriented partitioning heuristic methods.
- Successfully applied on both hardware and software designs
 - Significant reduction in test generation time.



Thank you !